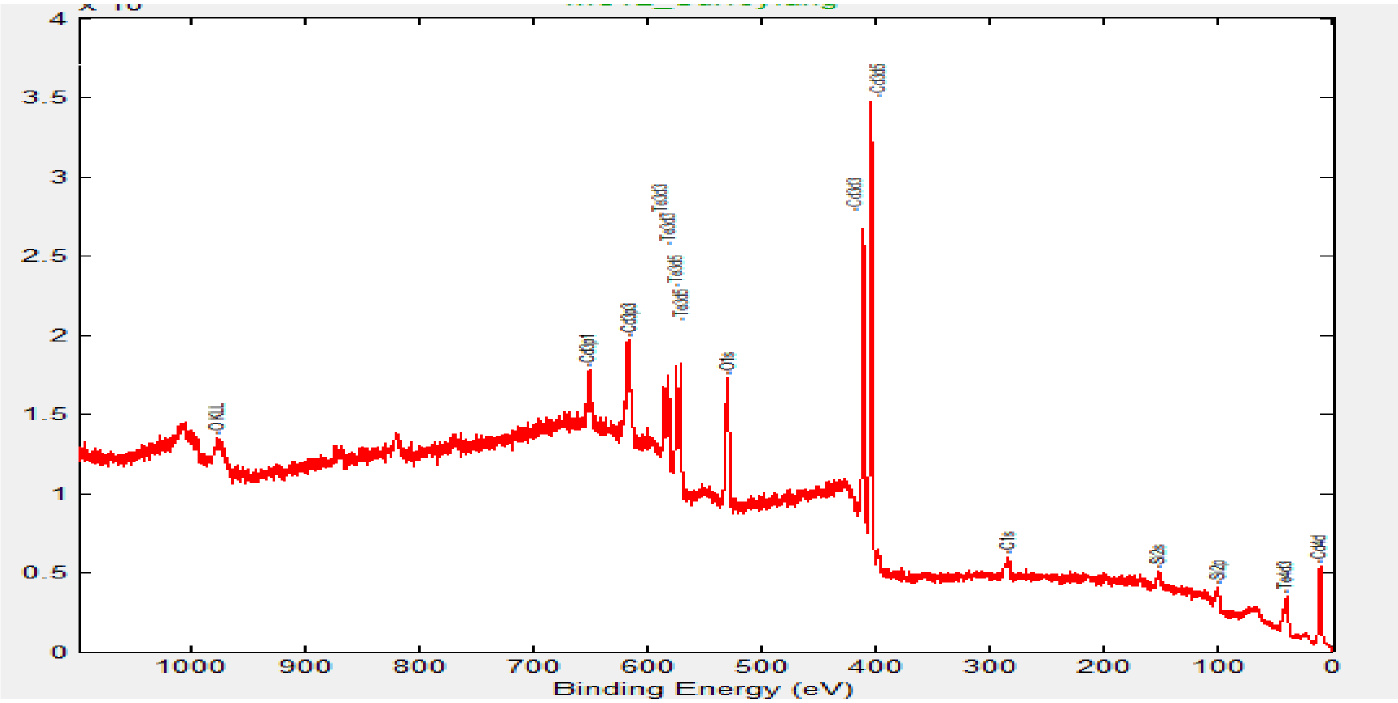

Figure 1 XPS survey of 100 cycles of CdTe ALD on HgCdTe device layer, confirming presence of CdTe

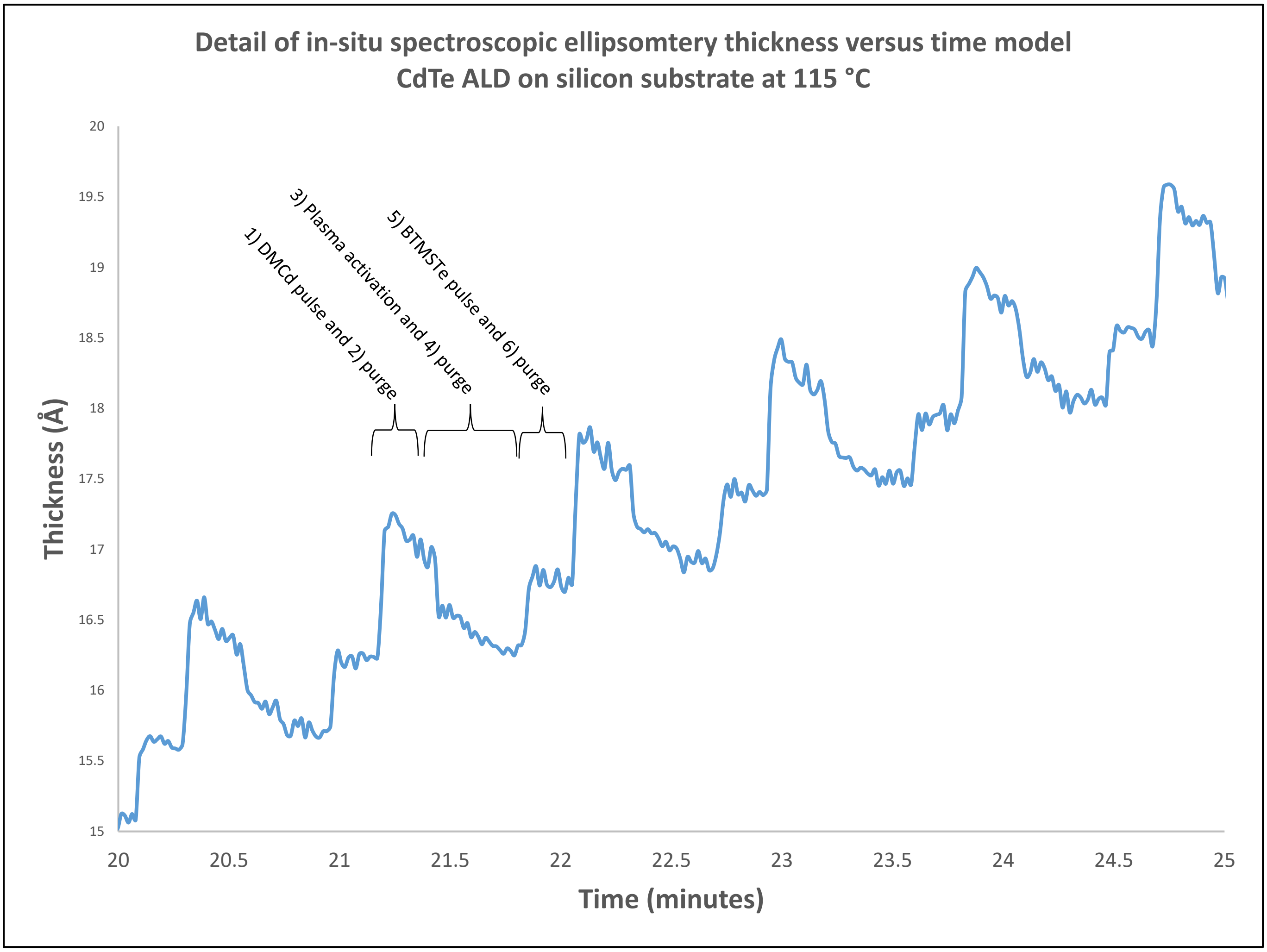

Figure 2 Dynamic in-situ spectroscopic ellipsometry of CdTe ALD on silicon substrate, indicating layer-by-layer growth